



μPARSET

Leading legend in high volume discrete testing

Application

- Final Test up to 6 or 12 pins
- Wafer Test

Key Feature

- Maximum supply and current per channel 400V/3A
- Handler and prober agnostic
- Small footprint 600 x 665 x 1235mm
- Very short test times
- 1 to 4 handlers
- Extreme flexibility
- Pin Electronics
- Max number of pins (FT and AT/QT): 6 or 12 pins
- High quality diagnostics and calibration
- High Accuracy
- User definable parameters
- Test Heads
 - Current amplifier for fast leakage measurement
 - Short and open pins close to DUT
 - Dedicated test hardware
- Multi-site testing
- Options:
 - μPFM - Floating mV meter (30mV/300mV/3V)
 - DCM - Digital Capacitance Meter (0.3 / 3 / 30 / 300pF)
 - μMUX - multiplexer - 4x24 pins for multi-site test
- Optional SEMI standard with SECS/GEM interface